

National Institute of Advanced Manufacturing Technology

Central Instrument Facility

Requisition form for X-Ray Diffraction: Texture Analysis (For External users)

Date:_____

Name of the user:	Name of the supervisor:			
Designation of user:	Department:			
Name and address of the institute /				
Industry:				
Contact No.	No. of Samples submitted:			
Email ID:	Nature of samples: Hazardous / Non-hazardous			

Test/s to be done: Please provide the following details:

S No.	Sample Name	hkl value	Sample height (in mm)	Crystal structure	Sample Recollection (Yes/No)

Remarks, if any:

Signature of user	Signature of supervisor	Signature of Head/In-charge

For CIF Use

Date of Completion:

Signature of Technician

Signature of user